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	U	I	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Ret
1	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20020031012 A1	20020314	26	Method for manufacturing non-volatile memory cell	365/185.26		
2	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20010015911 A1	20010823	26	Method for operating non-volatile memory cells	365/185.26		
3	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6353556 B1	20020305	23	Method for operating non-volatile memory cells	365/185.26	365/185.29; 365/185.33	
4	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6249459 B1	20010619	23	Circuit and method for equalizing erase rate of	365/185.26	365/185.22; 365/185.29	
5	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6219281 B1	20010417	23	System and method for erasing non-volatile memory	365/185.29	365/185.19; 365/185.33	
6	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6198662 B1	20010306	23	Circuit and method for pre-erasing/erasing flash	365/185.29	365/185.33; 365/218	
7	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6166962 A	20001226	23	Circuit and method for conditioning flash memory	365/185.3	365/185.24; 365/185.29	

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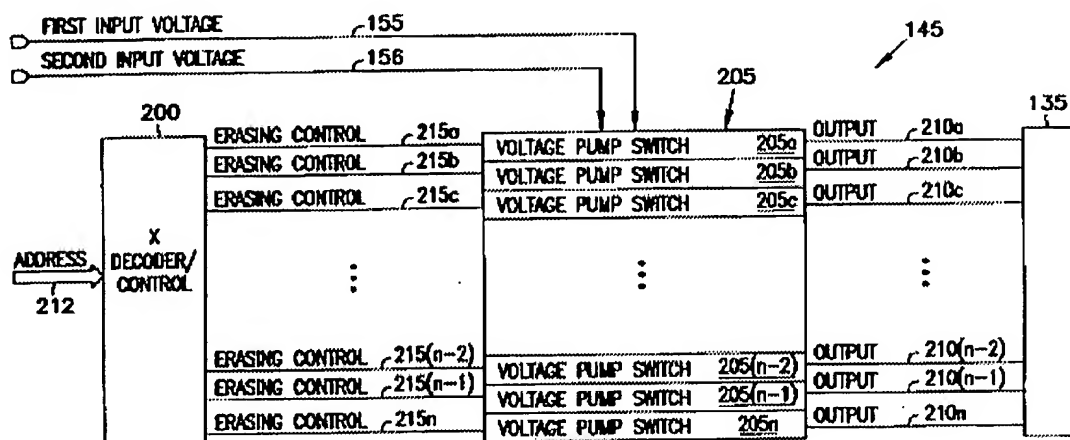


FIG. 2

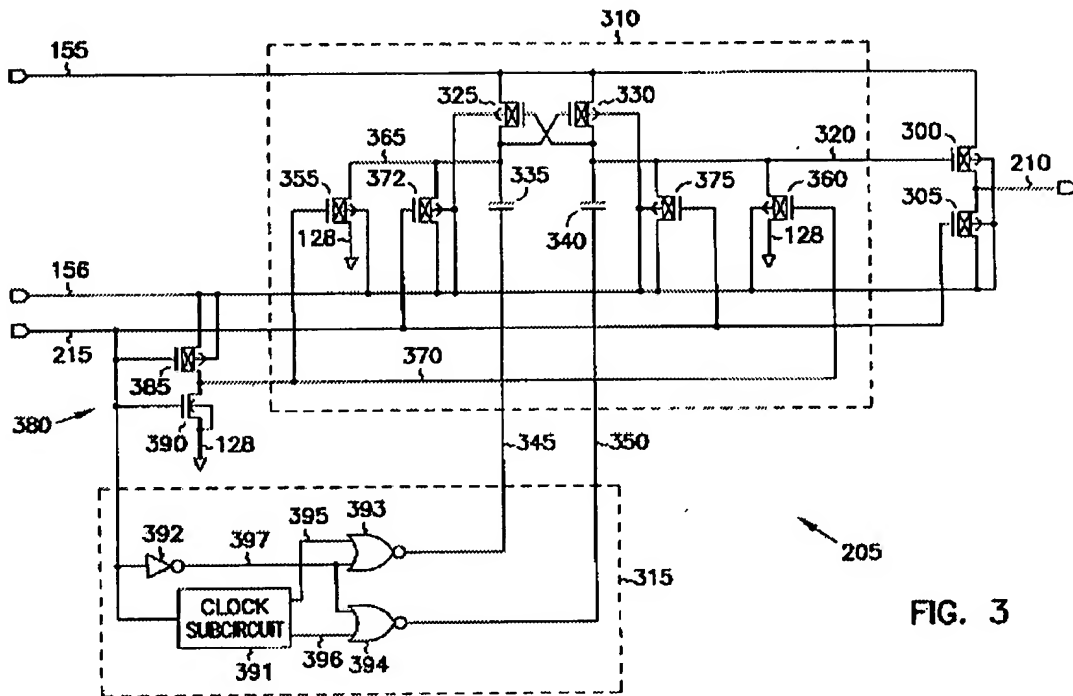
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6,023,427

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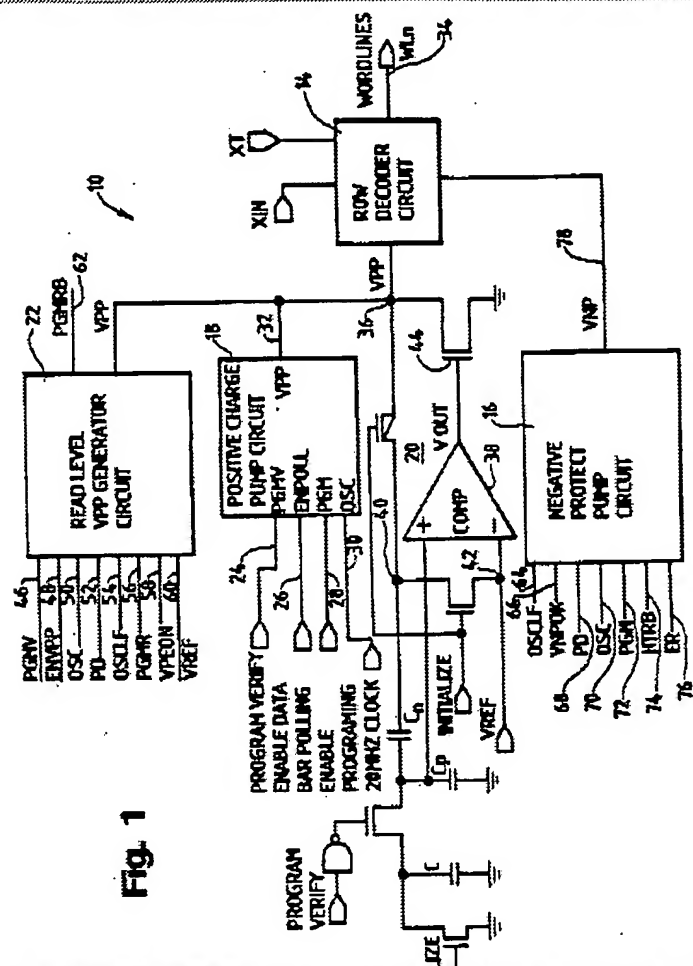


U.S. Patent

Feb. 8, 2000

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6,023,427



1700413724

Patent Number 3,282,170

145 Date of Patent Jan. 28, 1994

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**Associate Agent in Charge—**David Cole

**ABSTRACT**

A negative power supply for generating and supplying a regulated negative potential to control gates of electrical memory cells was described in an array of flash EPROMs. Memory cells during flash erasure included charge pumping stages (13) instead of a polarity change pump stages (101-106) for generating a high negative voltage, and capacitive means coupled to each stage of the charge pump stages for effectively canceling and threshold voltage drops in the charge pump stages. A regulated source (16) responsive to the high negative voltage and a reference potential is provided for generating the regulated negative potential so that it is independent of an external supply potential (VCC).

19 Claims, 5 Drawing Sheets

